

March 2013

FQPF8N60CF

N-Channel QFET® FRFET® MOSFET

600 V, 6.26 A, 1.5 Ω

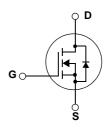
Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- 7.5 A, 600 V, $R_{DS(on)} = 1.2 \Omega(Max.) @V_{GS} = 10 V$, $I_D = 3.75 A$
- · Low Gate Charge (Typ. 28 nC)
- Low C_{rss} (Typ. 12 pF)
- 100% Avalanche Tested





Absolute Maximum Ratings

Symbol	Parameter		FQPF8N60CFT	Unit	
V _{DSS}	Drain-Source Voltage		600	V	
I _D	Drain Current - Continuous (T _C = 25°C)		6.26*	Α	
	- Continuous (T _C = 100°C)	3.96*	Α		
I _{DM}	Drain Current - Pulsed	(Note 1)	25*	Α	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	160	mJ	
I _{AR}	Avalanche Current	(Note 1)	6.26	Α	
E _{AR}	Repetitive Avalanche Energy (Note 1)		14.7	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns	
P_{D}	Power Dissipation (T _C = 25°C)		48	W	
	- Derate above 25°C		0.38	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

^{*} Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FQPF8N60CF	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	2.6	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQPF8N60CFT	FQPF8N60CFT	TO-220F			50

Electrical Characteristics $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Charac	teristics	,				
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_{D} = 250 μ A	600			V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C		0.7		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V			10	μА
		V _{DS} = 480 V, T _C = 125°C			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -30 V, V_{DS} = 0 V			-100	nA
On Charact	eristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 3.13 A		1.25	1.5	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D =3.13 A (Note 4)		8.7		S
Dynamic Ch	naracteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		965	1255	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		105	135	pF
C _{rss}	Reverse Transfer Capacitance			12	16	pF
Switching C	characteristics					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_{D} = 6.26 \text{A},$		16.5	45	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		60.5	130	ns
t _{d(off)}	Turn-Off Delay Time	41. 4.5		81	170	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		64.5	140	ns
Qg	Total Gate Charge	V _{DS} = 480 V, I _D = 6.26A,		28	36	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		4.5		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		12		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings					
I _S	Maximum Continuous Drain-Source Diode Forward Current				6.26	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				25	Α
V_{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 6.26 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 6.26 A,		82		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		242		nC

NOTES

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature
- 2. L = 7.3mH, I_{AS} = 6.26A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25°C
- 3. $I_{SD} \le 6.26$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ °C
- 4. Pulse Test : Pulse width $\leq 300 \mu s,$ Duty cycle $\leq 2\%$
- 5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

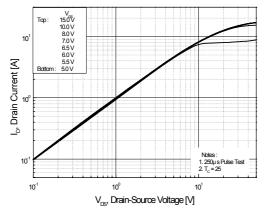


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

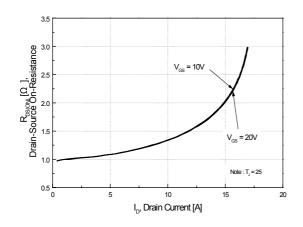


Figure 5. Capacitance Characteristics

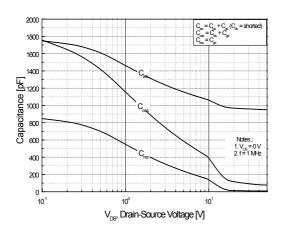


Figure 2. Transfer Characteristics

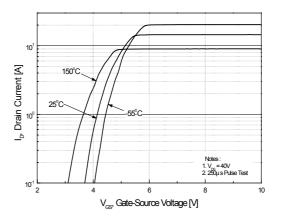


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

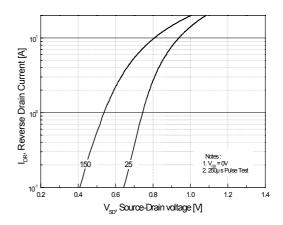
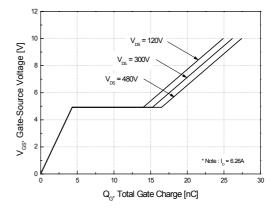


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

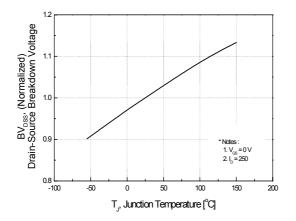


Figure 8. On-Resistance Variation vs. Temperature

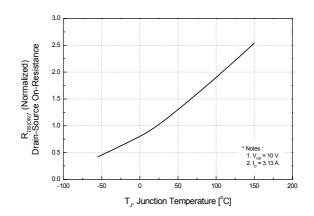
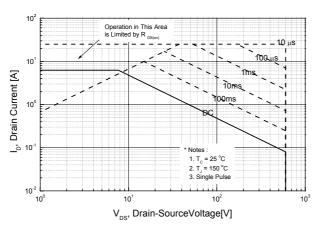


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature



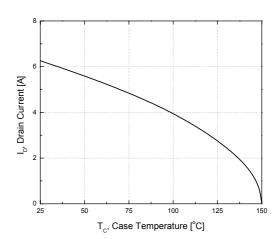
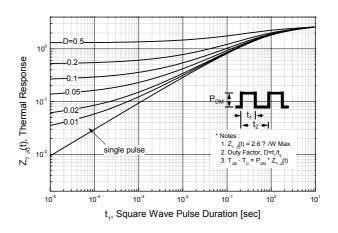
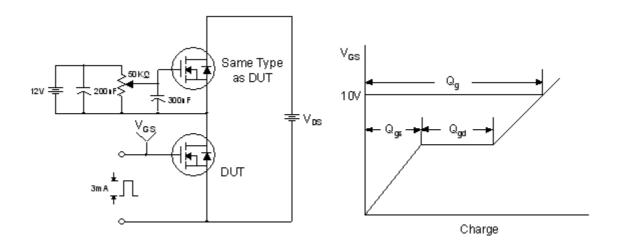


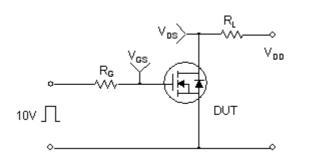
Figure 11. Transient Thermal Response Curve

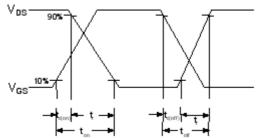


Gate Charge Test Circuit & Waveform

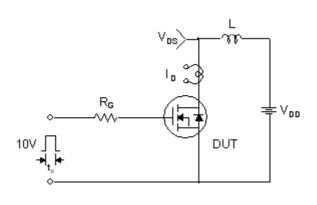


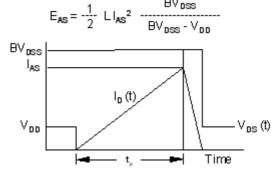
Resistive Switching Test Circuit & Waveforms



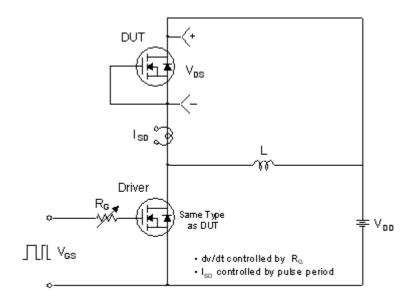


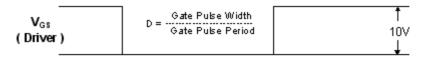
Unclamped Inductive Switching Test Circuit & Waveforms

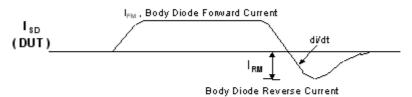


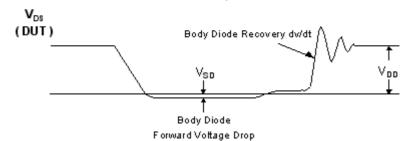


Peak Diode Recovery dv/dt Test Circuit & Waveforms









Mechanical Dimensions TO-220F 2.742.34 10.36 Α 9.96 Ø.3.28 (7.00) 3.08 3.40 (0.70) 3.20 SEE NOTE "F" SEE NOTE "F" 6.88 6.48 1 X 45° 16.07 15.67 16.00 15,60 (3.23) B 3 1.47 2.96 2.14 1.24 2.56 0.90 10.05 0.70 9.45 \oplus 0.50 M 30° 0.45 0.60 0.25 0.45 2.54 2.54 NOTES: A. EXCEPT WHERE NOTED CONFORMS TO EIAJ SC91A. EIAJ SC91A. B DOES NOT COMPLY EIAJ STD. VALUE. C. ALL DIMENSIONS ARE IN MILLIMETERS. D. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS. E. DIMENSION AND TOLERANCE AS PER ASME 4.90 <u>/B\</u> 4.50 Y14.5-1994. F. OPTION 1 - WITH SUPPORT PIN HOLE. OPTION 2 - NO SUPPORT PIN HOLE. G. DRAWING FILE NAME: TO220M03REV3 **Dimensions in Millimeters**





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